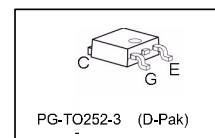
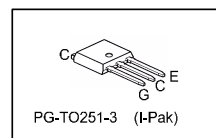
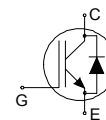


### IGBT with integrated diode in packages offering space saving advantage

#### Features:

TRENCHSTOP™ Reverse Conducting (RC) technology for 600V applications offering

- Optimised  $V_{CEsat}$  and  $V_F$  for low conduction losses
- Smooth switching performance leading to low EMI levels
- Very tight parameter distribution
- Operating range of 1 to 20kHz
- Maximum junction temperature 175°C
- Short circuit capability of 5 $\mu$ s
- Best in class current versus package size performance
- Qualified according to JEDEC for target applications
- Pb-free lead plating; RoHS compliant (for PG-TO252: solder temperature 260°C, MSL1)
- Complete product spectrum and PSpice Models:  
<http://www.infineon.com/igbt/>



#### Applications:

- Consumer motor drives

Type	$V_{CE}$	$I_C$	$V_{CEsat}, T_{vj}=25^\circ\text{C}$	$T_{vjmax}$	Marking	Package
IKD04N60R	600V	4A	1.65V	175°C	K04R60	PG-TO252-3
IKU04N60R	600V	4A	1.65V	175°C	K04R60	PG-TO251-3

#### Maximum ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CE}$	600	V
DC collector current, limited by $T_{vjmax}$ $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	$I_C$	8.0 4.0	A
Pulsed collector current, $t_b$ limited by $T_{vjmax}$	$I_{Cpuls}$	12.0	A
Turn off safe operating area $V_{CE} \leq 600\text{V}, T_{vj} \leq 175^\circ\text{C}$	-	12.0	A
Diode forward current, limited by $T_{vjmax}$ $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	$I_F$	8.0 4.0	A
Diode pulsed current, $t_b$ limited by $T_{vjmax}$	$I_{Fpuls}$	12.0	A
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Short circuit withstand time $V_{GE} = 15.0\text{V}, V_{CC} \leq 400\text{V}, T_{vj} \leq 150^\circ\text{C}$ Allowed number of short circuits < 1000 Time between short circuits: $\geq 1.0\text{s}$	$t_{SC}$	5	$\mu\text{s}$
Power dissipation $T_C = 25^\circ\text{C}$	$P_{tot}$	75.0	W
Operating junction temperature	$T_{vj}$	-40...+175	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55...+175	$^\circ\text{C}$
Soldering temperature, wavesoldering 1.6 mm (0.063 in.) from case for 10s	PG-TO251-3	260	$^\circ\text{C}$
for 10 s (according to JEDEC J-STA-020A)	PG-TO252-3	260	

**Thermal Resistance**

Parameter	Symbol	Conditions	Max. Value	Unit
<b>Characteristic</b>				
IGBT thermal resistance, junction - case	$R_{th(j-c)}$		2.00	K/W
Diode thermal resistance, junction - case	$R_{th(j-c)}$		4.50	K/W
Thermal resistance, min. footprint junction - ambient	$R_{th(j-a)}$	PG-TO252-3	75	K/W
Thermal resistance, 6cm <sup>2</sup> Cu on PCB junction - ambient	$R_{th(j-a)}$	PG-TO252-3	50	K/W
Thermal resistance junction - ambient	$R_{th(j-a)}$	PG-TO251-3	75	K/W

**Electrical Characteristic, at  $T_{vj} = 25^{\circ}\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Static Characteristic</b>						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE} = 0\text{V}$ , $I_C = 0.20\text{mA}$	600	-	-	V
Collector-emitter saturation voltage	$V_{CEsat}$	$V_{GE} = 15.0\text{V}$ , $I_C = 4.0\text{A}$ $T_{vj} = 25^{\circ}\text{C}$ $T_{vj} = 175^{\circ}\text{C}$	- -	1.65 1.85	2.10 -	V
Diode forward voltage	$V_F$	$V_{GE} = 0\text{V}$ , $I_F = 4.0\text{A}$ $T_{vj} = 25^{\circ}\text{C}$ $T_{vj} = 175^{\circ}\text{C}$	- -	1.70 1.70	2.10	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C = 0.07\text{mA}$ , $V_{CE} = V_{GE}$	4.3	5.0	5.7	V
Zero gate voltage collector current	$I_{CES}$	$V_{CE} = 600\text{V}$ , $V_{GE} = 0\text{V}$ $T_{vj} = 25^{\circ}\text{C}$ $T_{vj} = 175^{\circ}\text{C}$	- -	- -	40.0 1000.0	$\mu\text{A}$
Gate-emitter leakage current	$I_{GES}$	$V_{CE} = 0\text{V}$ , $V_{GE} = 20\text{V}$	-	-	100	nA
Transconductance	$g_{fs}$	$V_{CE} = 20\text{V}$ , $I_C = 4.0\text{A}$	-	2.2	-	S
Integrated gate resistor	$r_G$			none		$\Omega$

**Electrical Characteristic, at  $T_{vj} = 25^{\circ}\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Dynamic Characteristic</b>						
Input capacitance	$C_{ies}$	$V_{CE} = 25\text{V}$ , $V_{GE} = 0\text{V}$ , $f = 1\text{MHz}$	-	305	-	pF
Output capacitance	$C_{oes}$		-	18	-	
Reverse transfer capacitance	$C_{res}$		-	9	-	
Gate charge	$Q_G$	$V_{CC} = 480\text{V}$ , $I_C = 4.0\text{A}$ , $V_{GE} = 15\text{V}$	-	27.0	-	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	$L_E$	PG-TO252-3 PG-TO251-3	-	- 7.0	-	nH

**Switching Characteristic, Inductive Load, at  $T_{vj} = 25^{\circ}\text{C}$** 

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(on)}$	$T_{vj} = 25^{\circ}\text{C}$ , $V_{CC} = 400\text{V}$ , $I_C = 4.0\text{A}$ , $V_{GE} = 0.0/15.0\text{V}$ , $r_G = 43.0\Omega$ , $L_{\sigma} = 60\text{nH}$ , $C_{\sigma} = 40\text{pF}$ $L_{\sigma}$ , $C_{\sigma}$ from Fig. E	-	14	-	ns
Rise time	$t_r$		-	8	-	ns
Turn-off delay time	$t_{d(off)}$		-	146	-	ns
Fall time	$t_f$		-	171	-	ns
Turn-on energy	$E_{on}$		-	0.09	-	mJ
Turn-off energy	$E_{off}$		-	0.15	-	mJ
Total switching energy	$E_{ts}$		-	0.24	-	mJ

**Anti-Parallel Diode Characteristic, at  $T_{vj} = 25^{\circ}\text{C}$** 

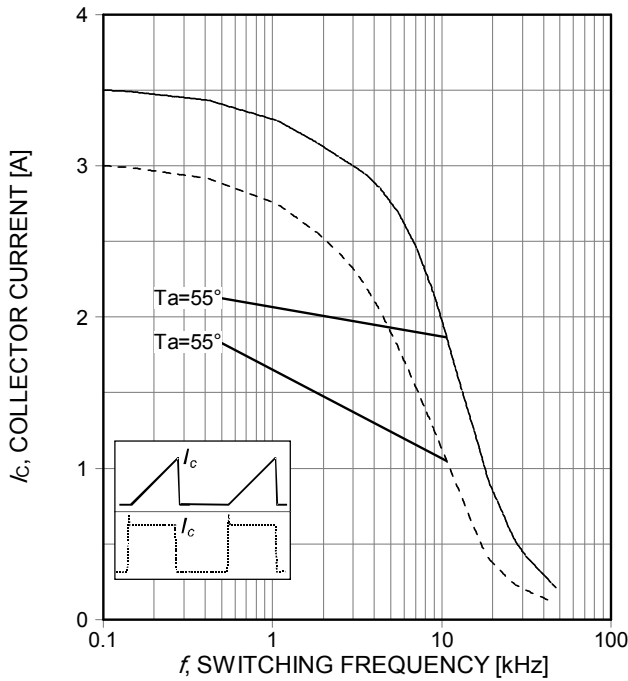
Diode reverse recovery time	$t_{rr}$	$T_{vj} = 25^{\circ}\text{C}$ , $V_R = 400\text{V}$ , $I_F = 4.0\text{A}$ , $di_F/dt = 600\text{A}/\mu\text{s}$	-	43	-	ns
Diode reverse recovery charge	$Q_{rr}$		-	0.22	-	$\mu\text{C}$
Diode peak reverse recovery current	$I_{rrm}$		-	7.6	-	A
Diode peak rate of fall of reverse recovery current during $t_b$	$di_{rr}/dt$		-	-330	-	$\text{A}/\mu\text{s}$

**Switching Characteristic, Inductive Load, at  $T_{vj} = 175^{\circ}\text{C}$** 

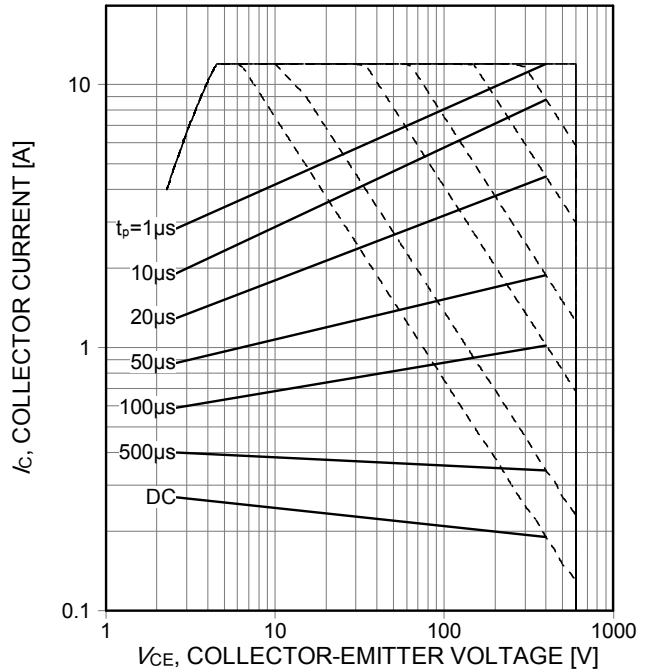
Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(on)}$	$T_{vj} = 175^{\circ}\text{C}$ , $V_{CC} = 400\text{V}$ , $I_C = 4.0\text{A}$ , $V_{GE} = 0.0/15.0\text{V}$ , $r_G = 43.0\Omega$ , $L_{\sigma} = 60\text{nH}$ , $C_{\sigma} = 40\text{pF}$ $L_{\sigma}$ , $C_{\sigma}$ from Fig. E	-	12	-	ns
Rise time	$t_r$		-	8	-	ns
Turn-off delay time	$t_{d(off)}$		-	177	-	ns
Fall time	$t_f$		-	165	-	ns
Turn-on energy	$E_{on}$		-	0.16	-	mJ
Turn-off energy	$E_{off}$		-	0.24	-	mJ
Total switching energy	$E_{ts}$		-	0.40	-	mJ

**Anti-Parallel Diode Characteristic, at  $T_{vj} = 175^{\circ}\text{C}$** 

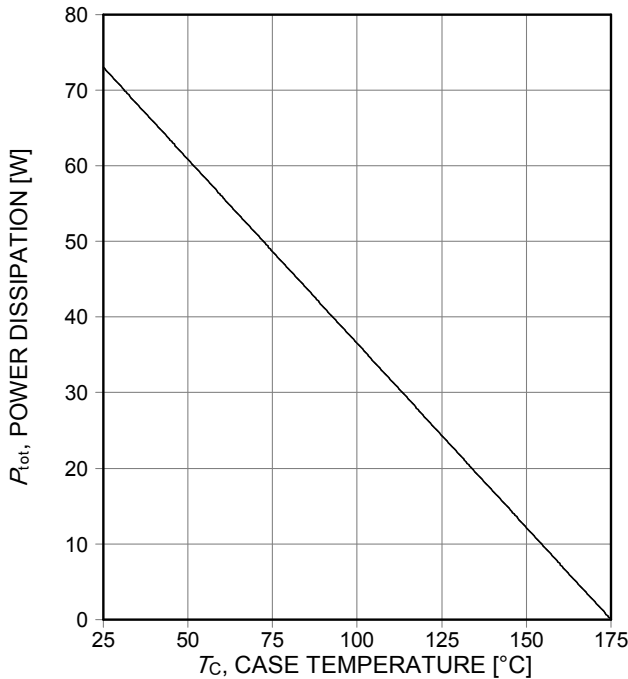
Diode reverse recovery time	$t_{rr}$	$T_{vj} = 175^{\circ}\text{C}$ , $V_R = 400\text{V}$ , $I_F = 4.0\text{A}$ , $di_F/dt = 600\text{A}/\mu\text{s}$	-	98	-	ns
Diode reverse recovery charge	$Q_{rr}$		-	0.52	-	$\mu\text{C}$
Diode peak reverse recovery current	$I_{rrm}$		-	11.0	-	A
Diode peak rate of fall of reverse recovery current during $t_b$	$di_{rr}/dt$		-	-200	-	$\text{A}/\mu\text{s}$



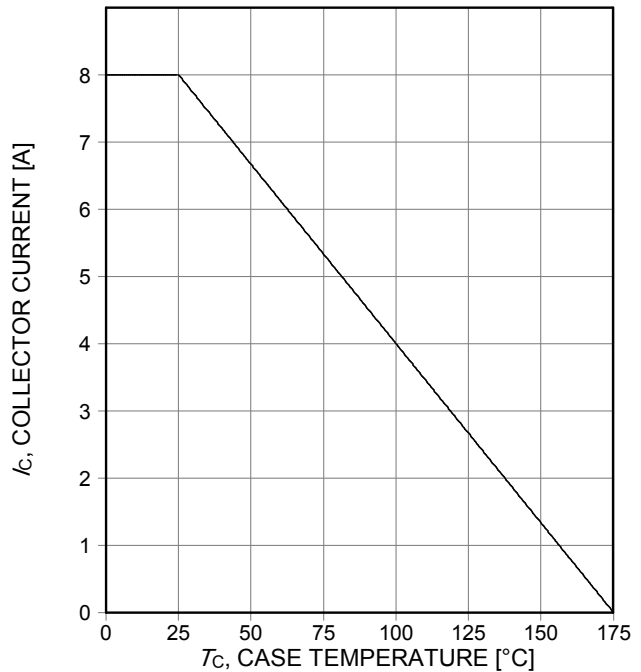
**Figure 1. Collector current as a function of switching frequency**  
 ( $T_{vj} \leq 175^\circ\text{C}$ ,  $D=0.5$ ,  $V_{CE}=400\text{V}$ ,  $V_{GE}=15/0\text{V}$ ,  $r_G=43\Omega$ , PCB Mounting, 6cm<sup>2</sup> Cu, Ptot=2,4W)



**Figure 2. Forward bias safe operating area**  
 ( $D=0$ ,  $T_C=25^\circ\text{C}$ ,  $T_{vj} \leq 175^\circ\text{C}$ ;  $V_{GE}=15\text{V}$ )



**Figure 3. Power dissipation as a function of case temperature**  
 ( $T_{vj} \leq 175^\circ\text{C}$ )



**Figure 4. Collector current as a function of case temperature**  
 ( $V_{GE} \geq 15\text{V}$ ,  $T_{vj} \leq 175^\circ\text{C}$ )

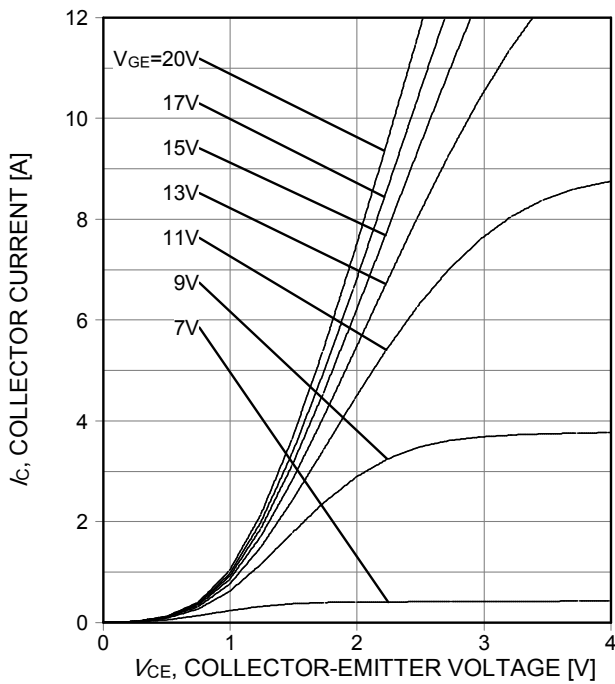


Figure 5. Typical output characteristic ( $T_{vj}=25^{\circ}\text{C}$ )

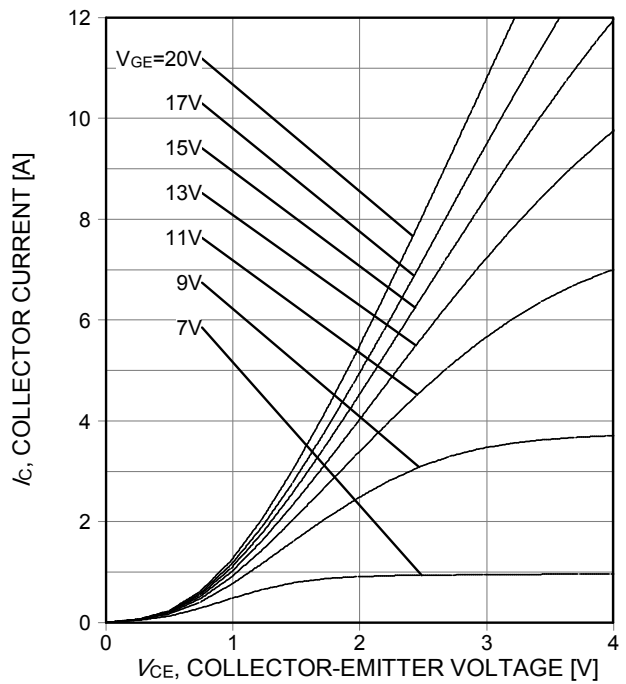


Figure 6. Typical output characteristic ( $T_{vj}=175^{\circ}\text{C}$ )

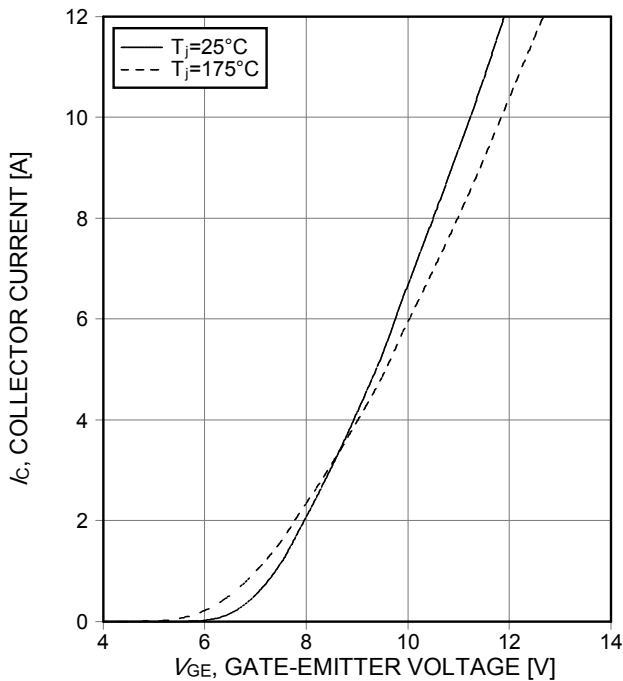


Figure 7. Typical transfer characteristic ( $V_{ce}=10\text{V}$ )

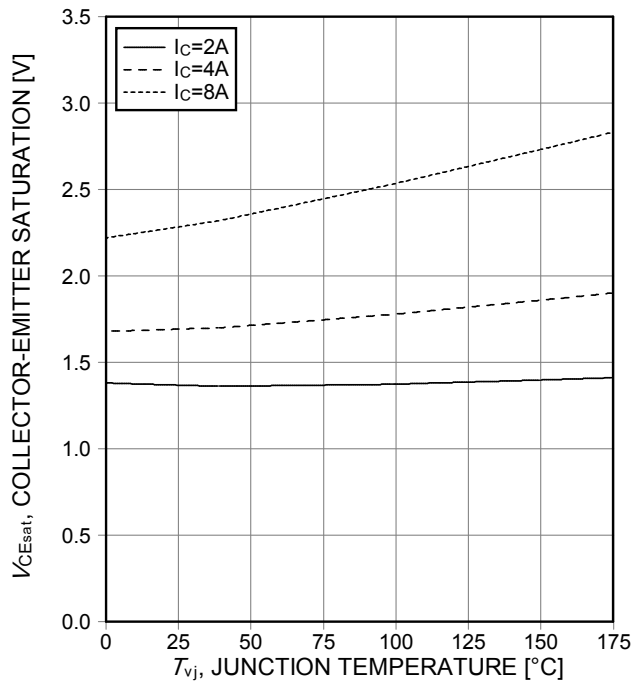
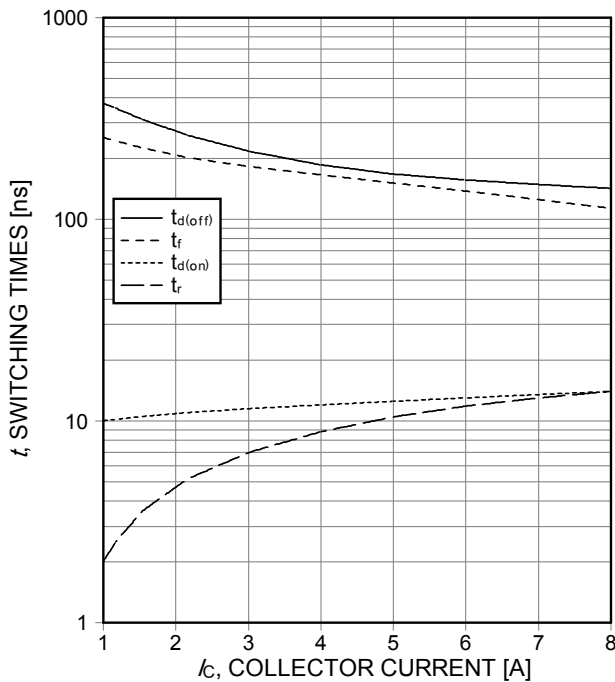
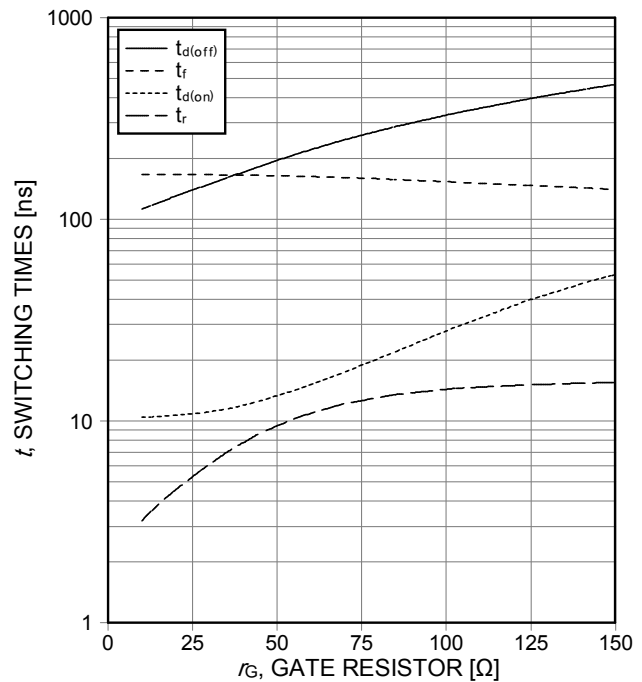


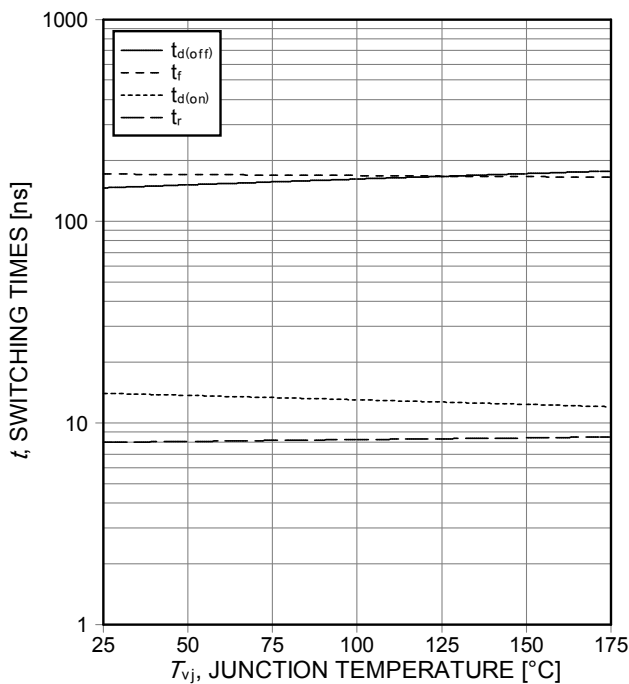
Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature ( $V_{ge}=15\text{V}$ )



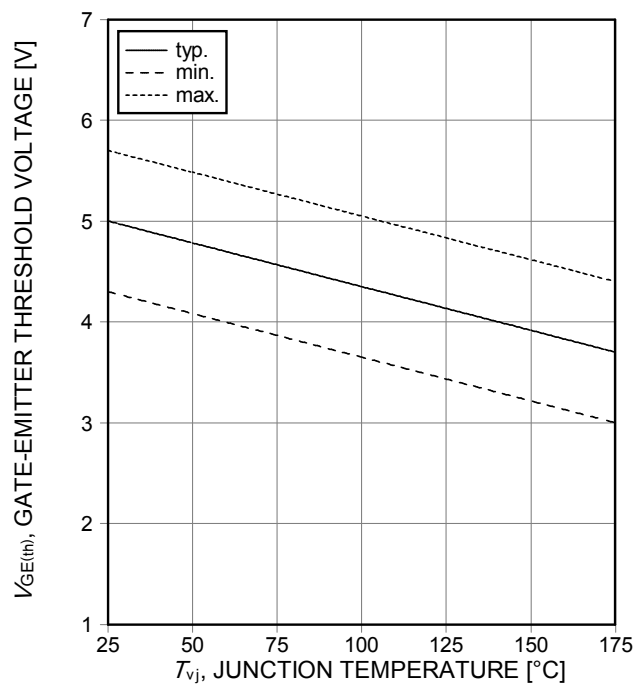
**Figure 9. Typical switching times as a function of collector current**  
 (inductive load,  $T_{vj}=175^{\circ}\text{C}$ ,  $V_{CE}=400\text{V}$ ,  $V_{GE}=15/0\text{V}$ ,  $r_G=43\Omega$ , Dynamic test circuit in Figure E)



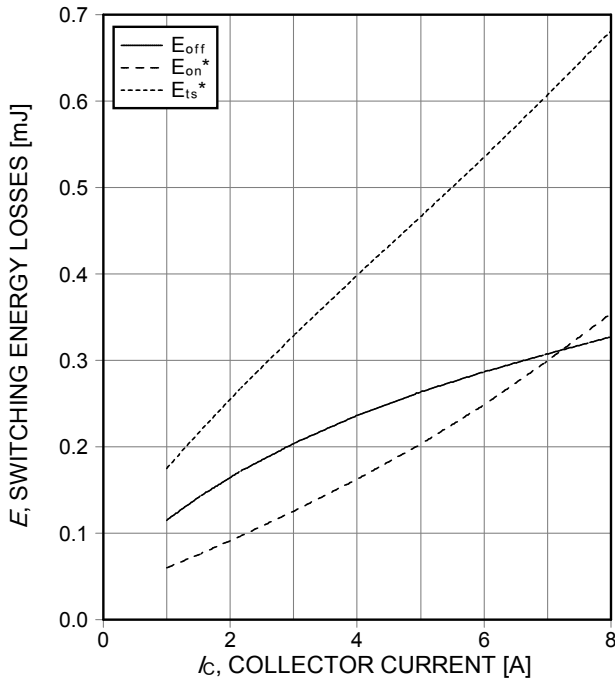
**Figure 10. Typical switching times as a function of gate resistor**  
 (inductive load,  $T_{vj}=175^{\circ}\text{C}$ ,  $V_{CE}=400\text{V}$ ,  $V_{GE}=15/0\text{V}$ ,  $I_C=4\text{A}$ , Dynamic test circuit in Figure E)



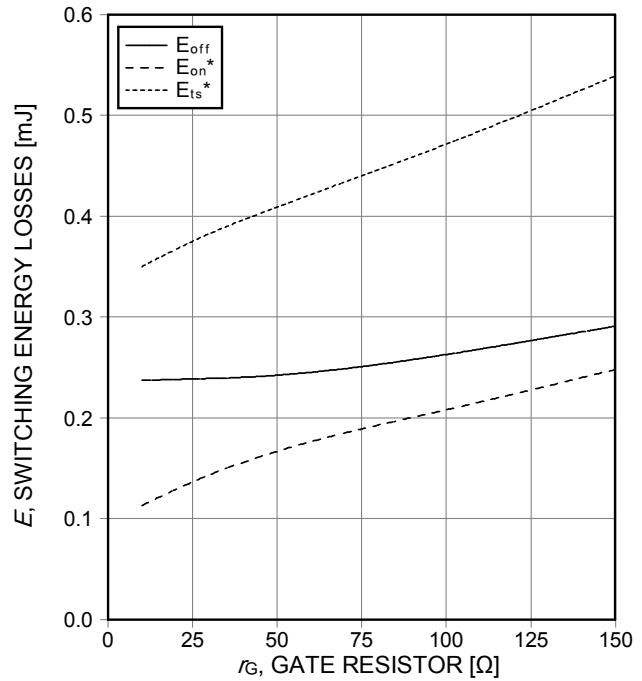
**Figure 11. Typical switching times as a function of junction temperature**  
 (inductive load,  $V_{CE}=400\text{V}$ ,  $V_{GE}=15/0\text{V}$ ,  $I_C=4\text{A}$ ,  $r_G=43\Omega$ , Dynamic test circuit in Figure E)



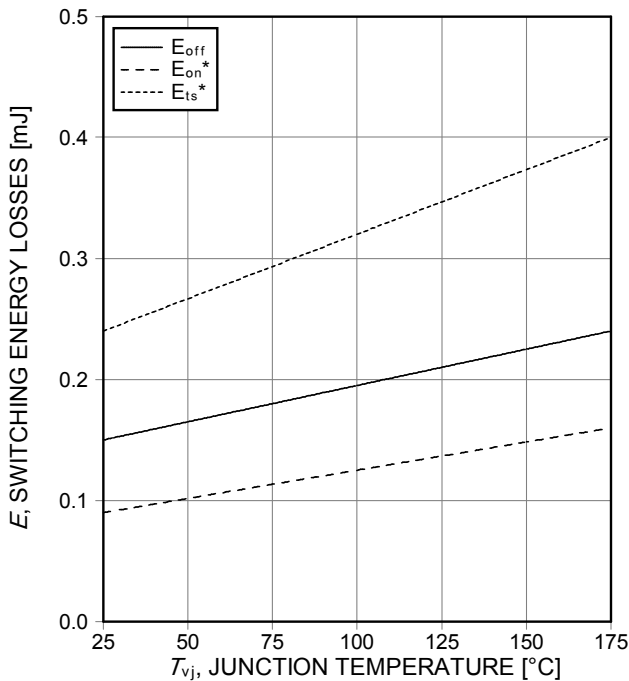
**Figure 12. Gate-emitter threshold voltage as a function of junction temperature**  
 ( $I_C=0,07\text{mA}$ )



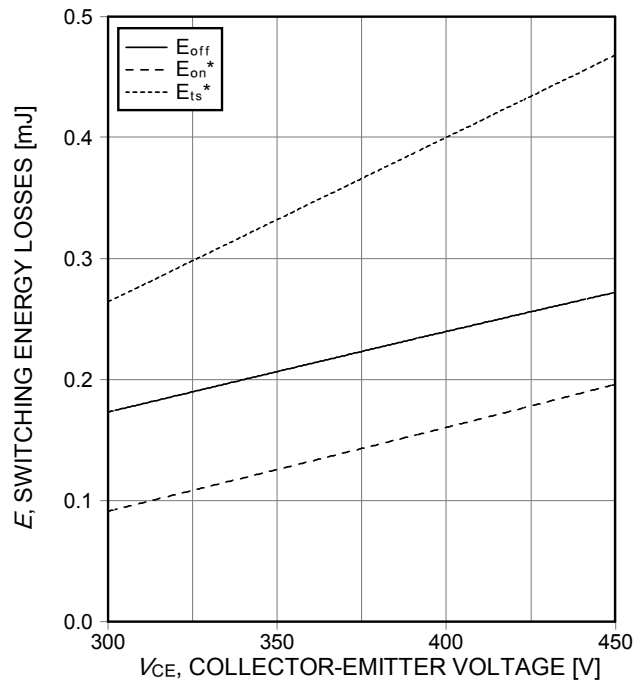
**Figure 13. Typical switching energy losses as a function of collector current**  
 (inductive load,  $T_{vj}=175^{\circ}\text{C}$ ,  $V_{CE}=400\text{V}$ ,  $V_{GE}=15/0\text{V}$ ,  $r_G=43\Omega$ , Dynamic test circuit in Figure E)



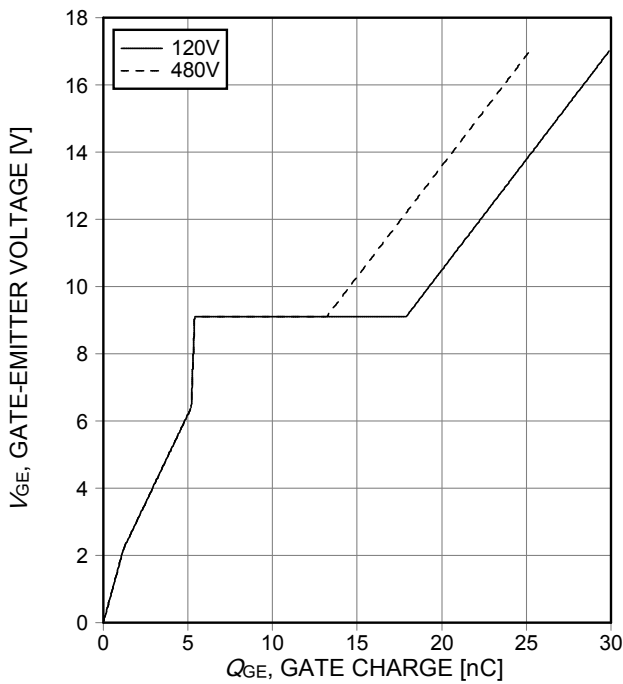
**Figure 14. Typical switching energy losses as a function of gate resistor**  
 (inductive load,  $T_{vj}=175^{\circ}\text{C}$ ,  $V_{CE}=400\text{V}$ ,  $V_{GE}=15/0\text{V}$ ,  $I_C=4\text{A}$ , Dynamic test circuit in Figure E)



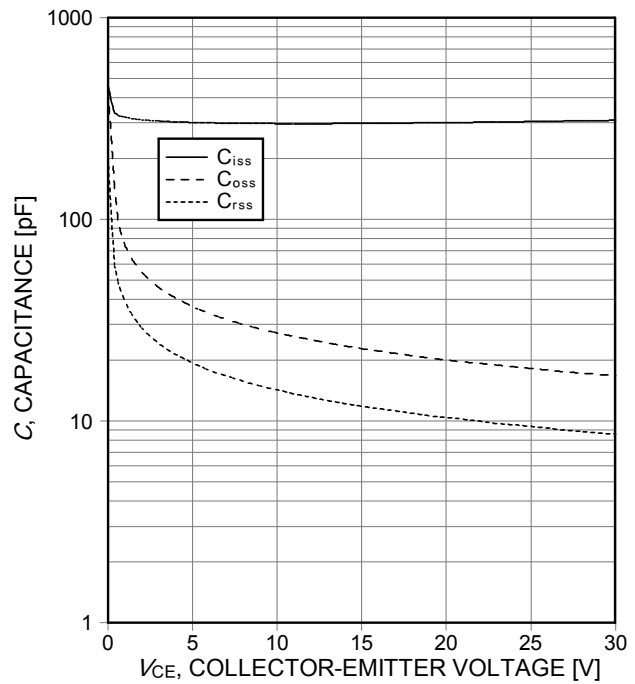
**Figure 15. Typical switching energy losses as a function of junction temperature**  
 (inductive load,  $V_{CE}=400\text{V}$ ,  $V_{GE}=15/0\text{V}$ ,  $I_C=4\text{A}$ ,  $r_G=43\Omega$ , Dynamic test circuit in Figure E)



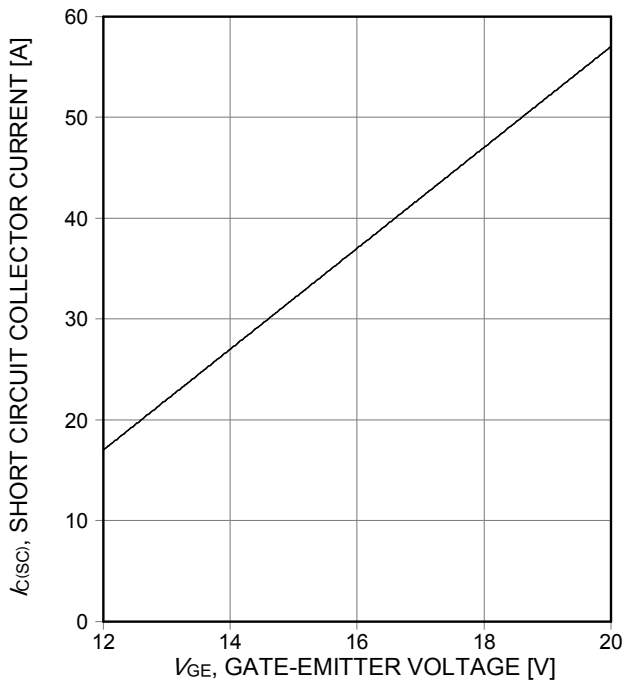
**Figure 16. Typical switching energy losses as a function of collector emitter voltage**  
 (inductive load,  $T_{vj}=175^{\circ}\text{C}$ ,  $V_{GE}=15/0\text{V}$ ,  $I_C=4\text{A}$ ,  $r_G=43\Omega$ , Dynamic test circuit in Figure E)



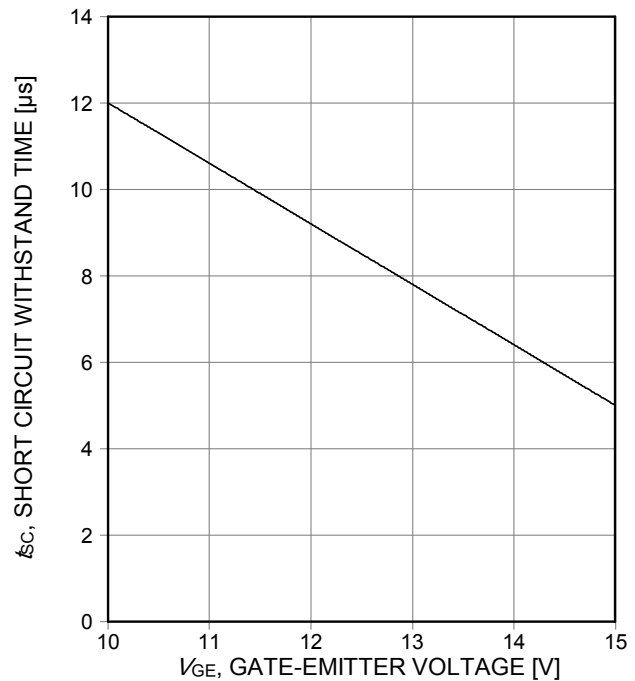
**Figure 17. Typical gate charge**  
( $I_C=4A$ )



**Figure 18. Typical capacitance as a function of collector-emitter voltage**  
( $V_{GE}=0V$ ,  $f=1MHz$ )



**Figure 19. Typical short circuit collector current as a function of gate-emitter voltage**  
( $V_{CE} \leq 400V$ , start at  $T_{vj}=25^\circ C$ )



**Figure 20. Short circuit withstand time as a function of gate-emitter voltage**  
( $V_{CE} \leq 400V$ , start at  $T_{vj}=150^\circ C$ )



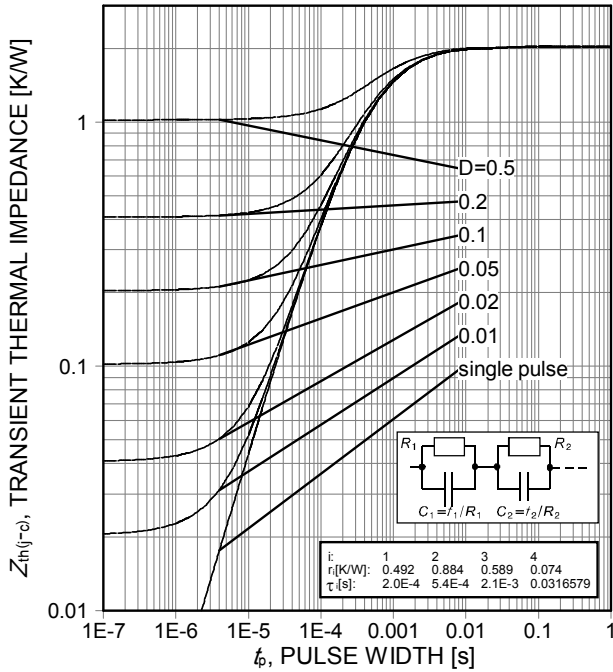


Figure 21. IGBT transient thermal impedance <sup>1)</sup>  
( $D = t_p/T$ )

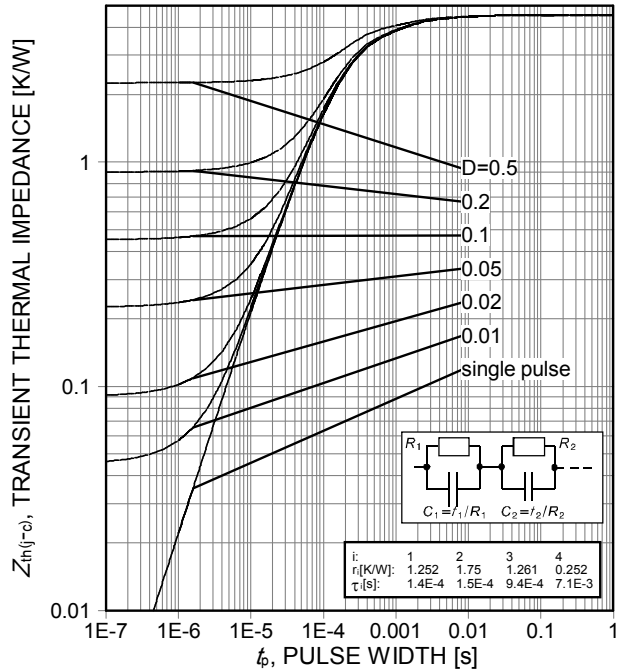


Figure 22. Diode transient thermal impedance as a function of pulse width <sup>1)</sup>  
( $D = t_p/T$ )

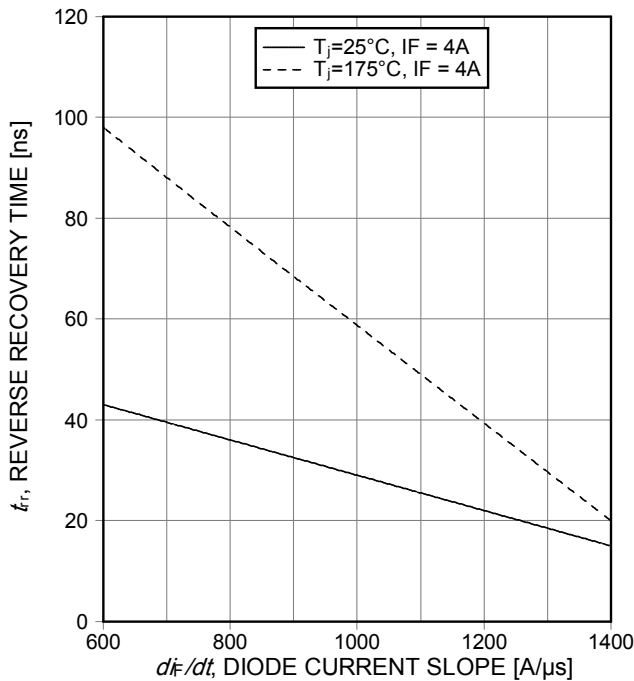


Figure 23. Typical reverse recovery time as a function of diode current slope  
( $V_R = 400V$ )

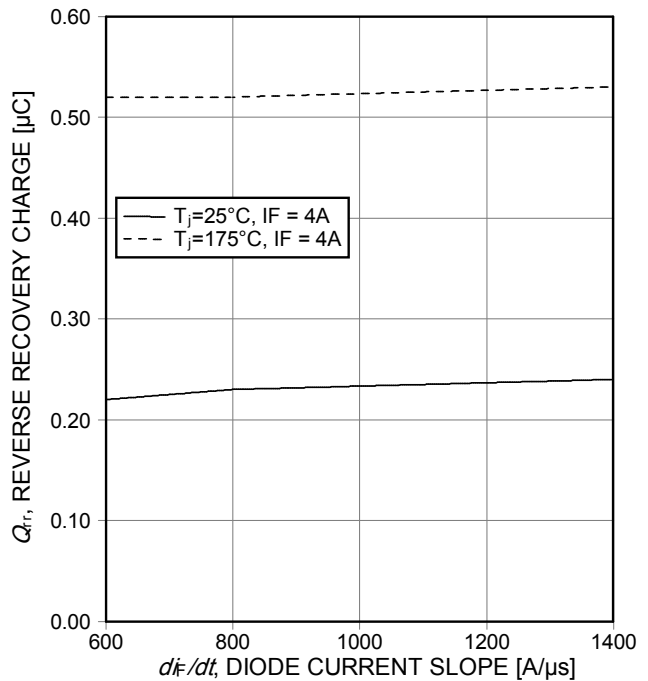
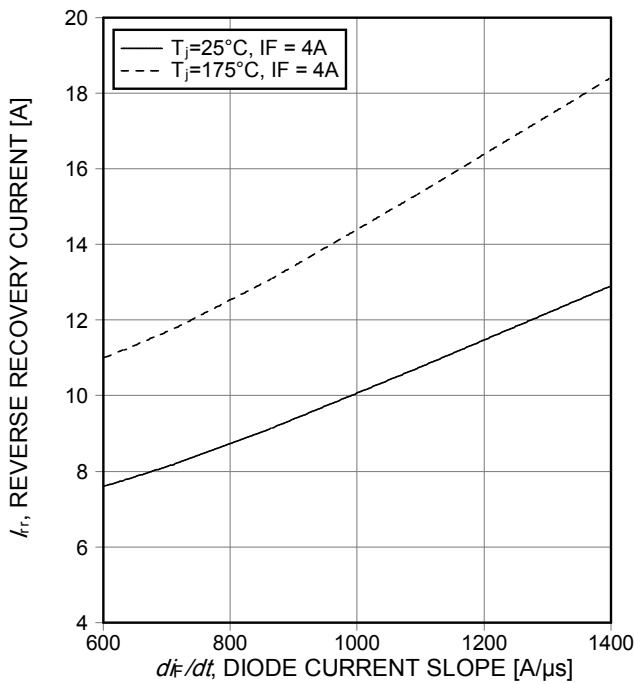
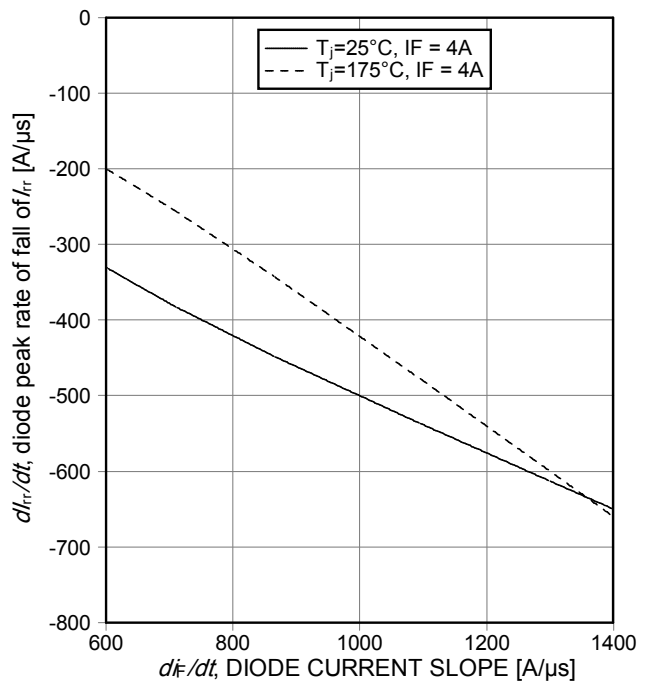


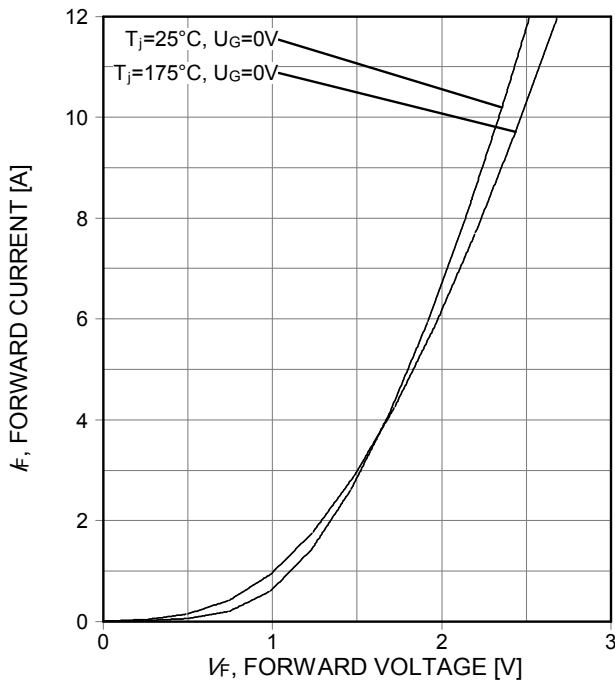
Figure 24. Typical reverse recovery charge as a function of diode current slope  
( $V_R = 400V$ )



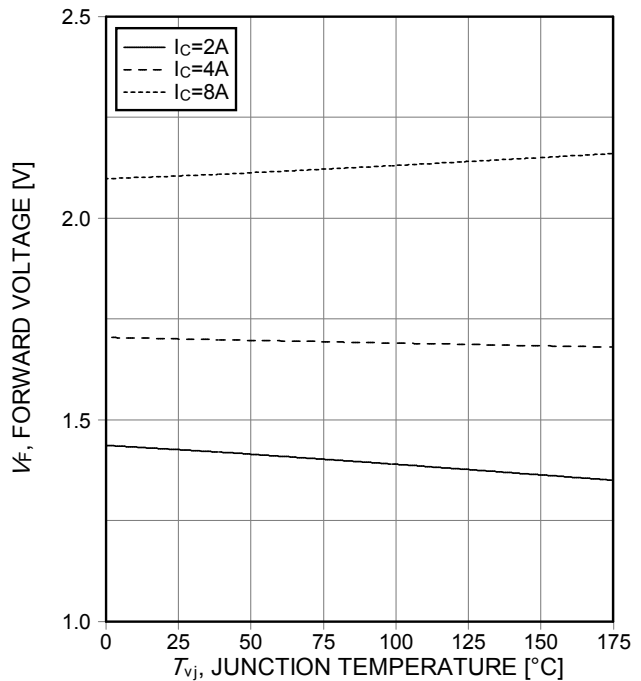
**Figure 25. Typical reverse recovery current as a function of diode current slope ( $V_R=400V$ )**



**Figure 26. Typical diode peak rate of fall of reverse recovery current as a function of diode current slope ( $V_R=400V$ )**

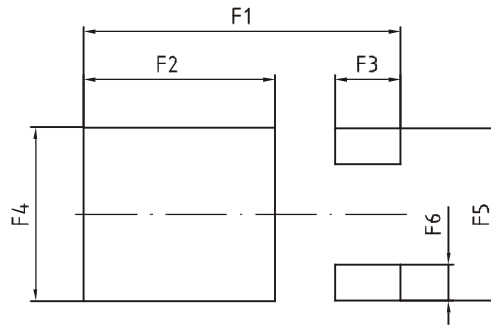
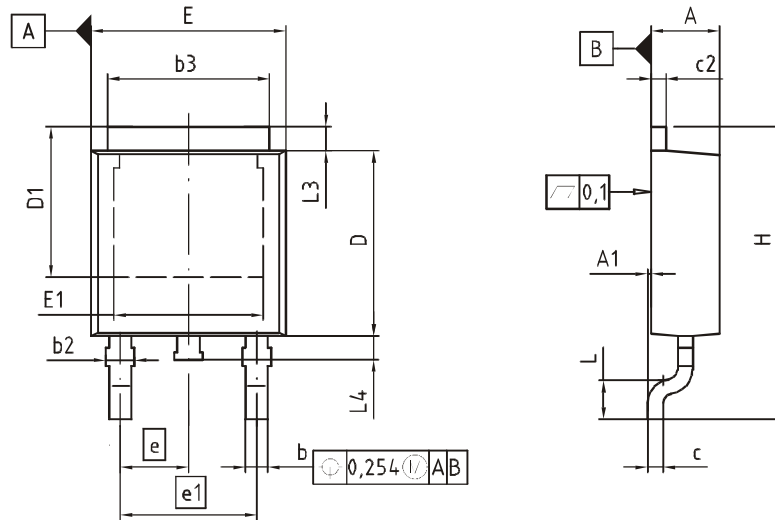


**Figure 27. Typical diode forward current as a function of forward voltage**



**Figure 28. Typical diode forward voltage as a function of junction temperature**

T0252-3-1/-11/-21/-311/-341



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.16	2.41	0.085	0.095
A1	0.00	0.15	0.000	0.006
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b3	5.00	5.50	0.197	0.217
c	0.46	0.60	0.018	0.024
c2	0.46	0.98	0.018	0.039
D	5.97	6.22	0.235	0.245
D1	5.02	5.84	0.198	0.230
E	6.40	6.73	0.252	0.265
E1	4.70	5.21	0.185	0.205
e	2.29		0.090	
e1	4.57		0.180	
N	3		3	
H	9.40	10.48	0.370	0.413
L	1.18	1.70	0.046	0.067
L3	0.90	1.25	0.035	0.049
L4	0.51	1.00	0.020	0.039
F1	10.50	10.70	0.413	0.421
F2	6.30	6.50	0.248	0.256
F3	2.10	2.30	0.083	0.091
F4	5.70	5.90	0.224	0.232
F5	5.66	5.86	0.223	0.231
F6	1.10	1.30	0.043	0.051

DOCUMENT NO.  
Z8B00003328

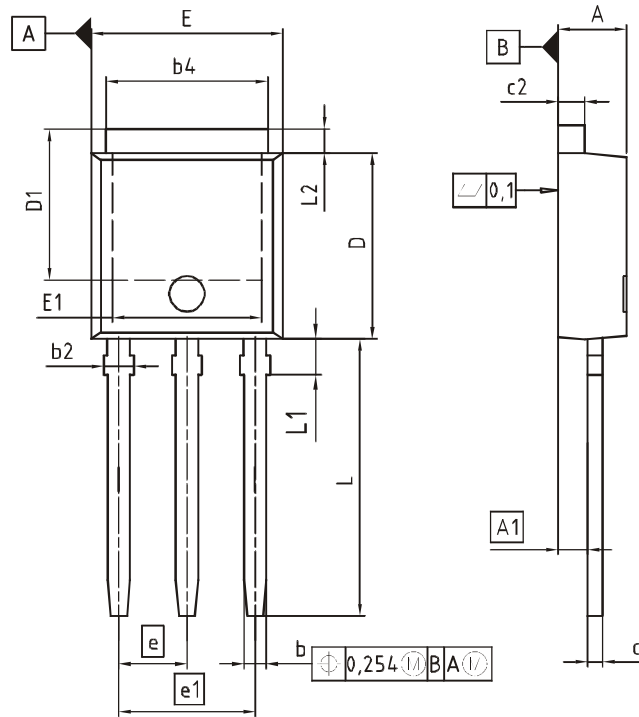
SCALE

EUROPEAN PROJECTION

ISSUE DATE  
19-10-2007

REVISION  
03

T0251-3-21/-341



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.16	2.41	0.085	0.095
A1	0.90	1.14	0.035	0.045
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b4	4.95	5.50	0.195	0.217
c	0.46	0.60	0.018	0.024
c2	0.46	0.89	0.018	0.035
D	5.97	6.22	0.235	0.245
D1	5.04	5.77	0.198	0.227
E	6.35	6.73	0.250	0.265
E1	4.70	5.21	0.185	0.205
e	2.29		0.090	
e1	4.57		0.180	
N	3		3	
L	8.89	9.65	0.350	0.380
L1	1.90	2.29	0.075	0.090
L2	0.89	1.37	0.035	0.054

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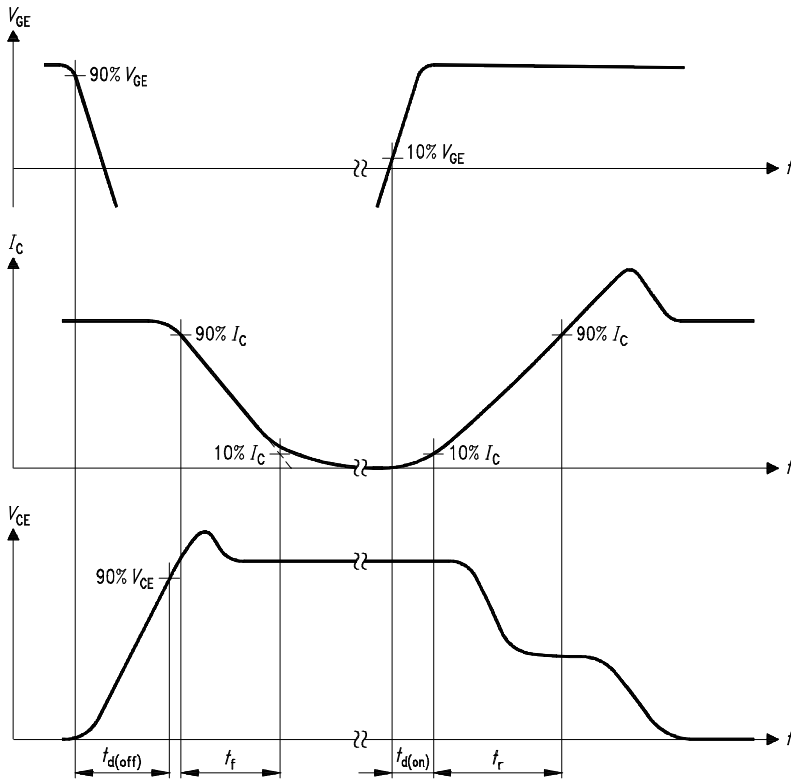


Figure A. Definition of switching times

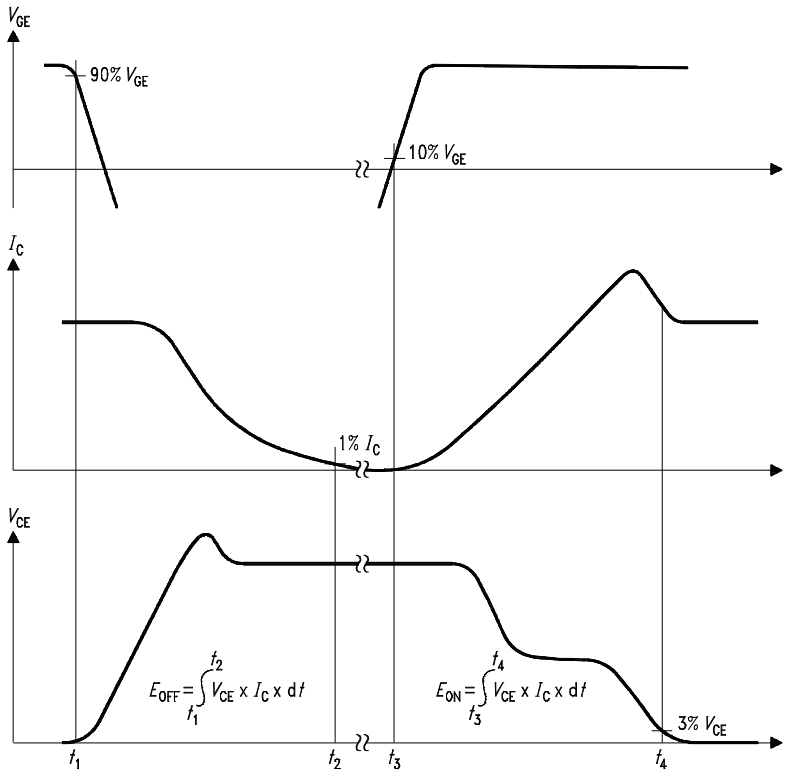


Figure B. Definition of switching losses

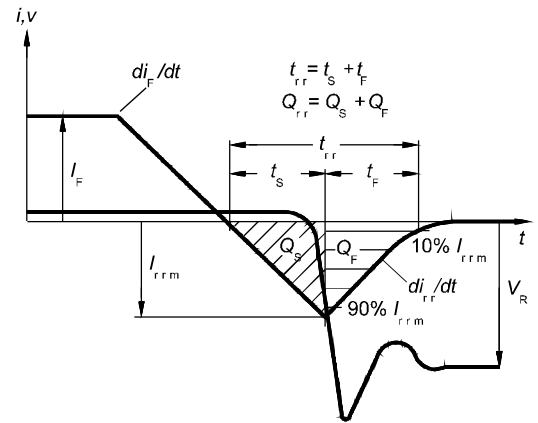


Figure C. Definition of diodes switching characteristics

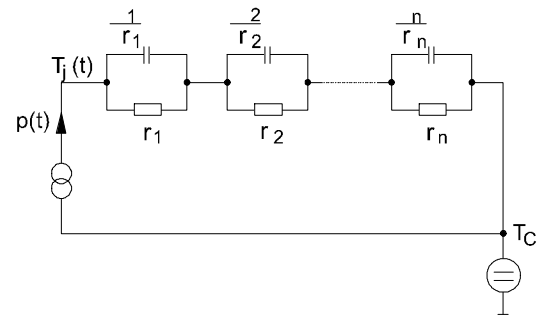


Figure D. Thermal equivalent circuit

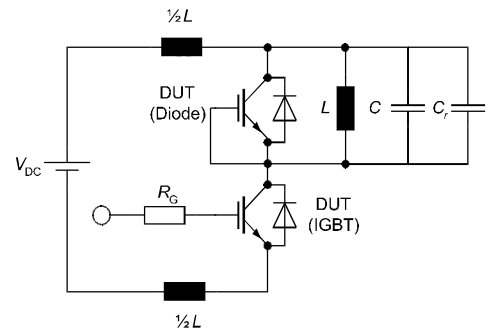


Figure E. Dynamic test circuit  
Leakage inductance  $L = 180\text{nH}$ ,  
Stray capacitor  $C_s = 40\text{pF}$ ,  
Relief capacitor  $C_r = 1\text{nF}$   
(only for ZVT switching)



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<sup>1)</sup> Rth/Zth based on single cooling pulse. Please be aware that a correct Rth measurement of this device, is not possible using a thermocouple.